



## Description

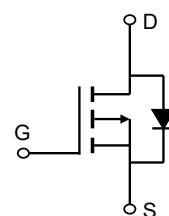
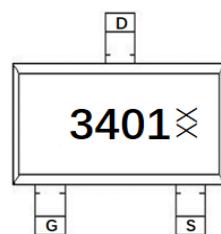
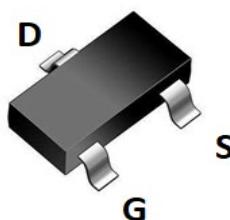
### JMT P-channel Enhancement Mode Power MosFET

#### Features

- -30V, -4.2A
- $R_{DS(ON)} < 47m\Omega$  @  $V_{GS} = -10V$
- $R_{DS(ON)} < 53m\Omega$  @  $V_{GS} = -4.5V$
- $R_{DS(ON)} < 68m\Omega$  @  $V_{GS} = -2.5V$
- Advanced Trench Technology
- Excellent  $R_{DS(ON)}$  and Low Gate Charge
- Lead Free

#### Applications

- Load Switch
- PWM Application
- Power Management



SOT-23-3L Top View

Marking and Pin Assignment

Schematic Diagram

#### Package Marking and Ordering Information

Device Marking	Device	Outline	Package	Reel Size	Reel(pcs)	Per Carton (pcs)
3401	JMTJ3401A	TAPING	SOT-23-3L	7"	3000	120000

#### Absolute Maximum Ratings (@ $T_A = 25^\circ C$ unless otherwise specified)

Symbol	Parameter		Value		Units
$V_{DS}$	Drain-to-Source Voltage		-30		V
$V_{GS}$	Gate-to-Source Voltage		$\pm 12$		V
$I_D$	Continuous Drain Current	$T_A = 25^\circ C$	-4.2		A
		$T_A = 100^\circ C$	-3		
$I_{DM}$	Pulsed Drain Current <sup>(1)</sup>		-17		A
$P_D$	Power Dissipation	$T_A = 25^\circ C$	1.1		W
$R_{\theta JA}$	Thermal Resistance, Junction to Ambient <sup>(2)</sup>		119		$^\circ C/W$
$T_J, T_{STG}$	Junction & Storage Temperature Range		-55 to 150		$^\circ C$

**Electrical Characteristics** ( $T_J = 25^\circ\text{C}$  unless otherwise specified)

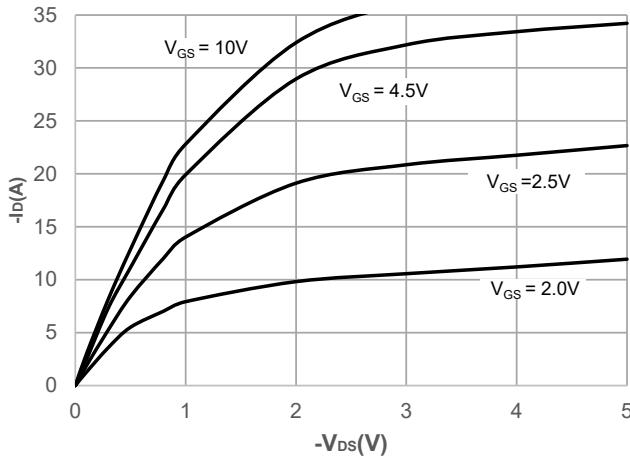
Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
<b>Off Characteristics</b>						
$V_{(\text{BR})\text{DSS}}$	Drain-Source Breakdown Voltage	$I_D = -250\mu\text{A}, V_{GS} = 0\text{V}$	-30	-	-	V
$I_{\text{DSS}}$	Zero Gate Voltage Drain Current	$V_{DS} = -30\text{V}, V_{GS} = 0\text{V}$	-	-	1.0	$\mu\text{A}$
$I_{\text{GSS}}$	Gate-Body Leakage Current	$V_{DS} = 0\text{V}, V_{GS} = \pm 12\text{V}$	-	-	$\pm 100$	nA
<b>On Characteristics</b>						
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{DS} = V_{GS}, I_D = -250\mu\text{A}$	-0.6	-0.9	-1.3	V
$R_{\text{DS(ON)}}$	Static Drain-Source ON-Resistance <sup>(3)</sup>	$V_{GS} = -10\text{V}, I_D = -4\text{A}$	-	36	47	$\text{m}\Omega$
		$V_{GS} = -4.5\text{V}, I_D = -3\text{A}$	-	41	53	$\text{m}\Omega$
		$V_{GS} = -2.5\text{V}, I_D = -1\text{A}$	-	52	68	$\text{m}\Omega$
<b>Dynamic Characteristics</b>						
$C_{\text{iss}}$	Input Capacitance	$V_{GS} = 0\text{V}, V_{DS} = -15\text{V}, f = 1\text{MHz}$	-	762	-	pF
$C_{\text{oss}}$	Output Capacitance		-	74	-	pF
$C_{\text{rss}}$	Reverse Transfer Capacitance		-	61	-	pF
$Q_g$	Total Gate Charge	$V_{GS} = 0 \text{ to } -4.5\text{V}$ $V_{DS} = -15\text{V}, I_D = -3\text{A}$	-	8	-	nC
$Q_{gs}$	Gate Source Charge		-	2	-	nC
$Q_{gd}$	Gate Drain("Miller") Charge		-	2	-	nC
<b>Switching Characteristics</b>						
$t_{d(on)}$	Turn-On Delay Time	$V_{GS} = -4.5\text{V}, V_{DD} = -15\text{V}$ $I_D = -3\text{A}, R_{\text{GEN}} = 3\Omega$	-	8	-	ns
$t_r$	Turn-On Rise Time		-	16	-	ns
$t_{d(off)}$	Turn-Off Delay Time		-	46	-	ns
$t_f$	Turn-Off Fall Time		-	34	-	ns
<b>Drain-Source Diode Characteristics and Max Ratings</b>						
$I_S$	Maximum Continuous Drain to Source Diode Forward Current	-	-	-4.2	A	
$I_{SM}$	Maximum Pulsed Drain to Source Diode Forward Current	-	-	-17	A	
$V_{SD}$	Drain to Source Diode Forward Voltage	$V_{GS} = 0\text{V}, I_S = -4.2\text{A}$	-	-	-1.2	V
$trr$	Body Diode Reverse Recovery Time	$I_F = -3\text{A}, di/dt = 100\text{A/us}$	-	8	-	ns
$Qrr$	Body Diode Reverse Recovery Charge		-	3	-	nC

Notes: 1. Repetitive Rating: Pulse Width Limited by Maximum Junction Temperature.

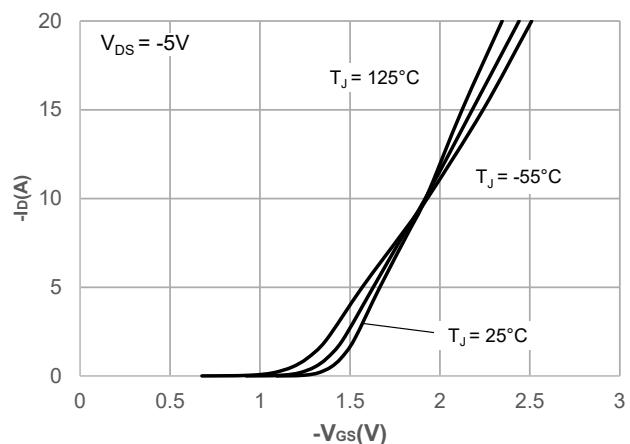
2.  $R_{\theta JA}$  is measured with the device mounted on a 1inch<sup>2</sup> pad of 2oz copper FR4 PCB3. Pulse Test: Pulse Width  $\leq 300\mu\text{s}$ , Duty Cycle  $\leq 0.5\%$ .

## Typical Performance Characteristics

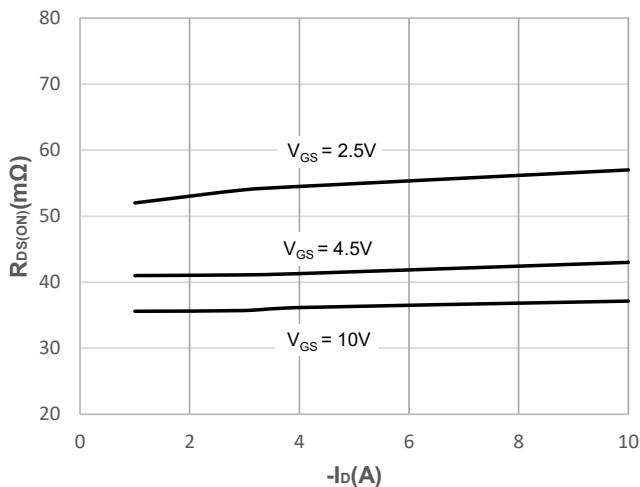
**Figure 1: Output Characteristics**



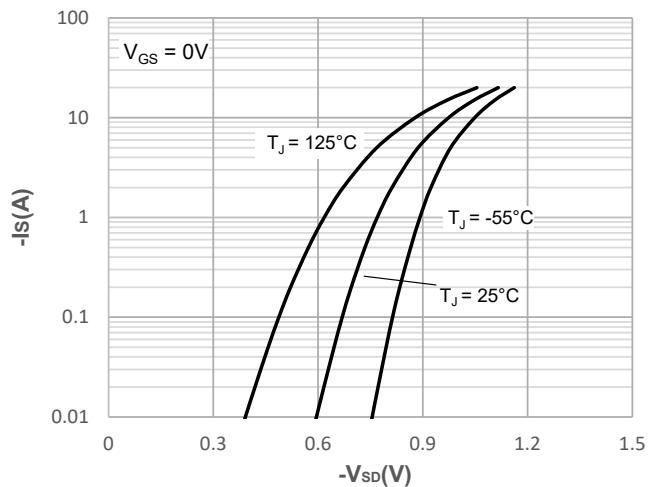
**Figure 2: Typical Transfer Characteristics**



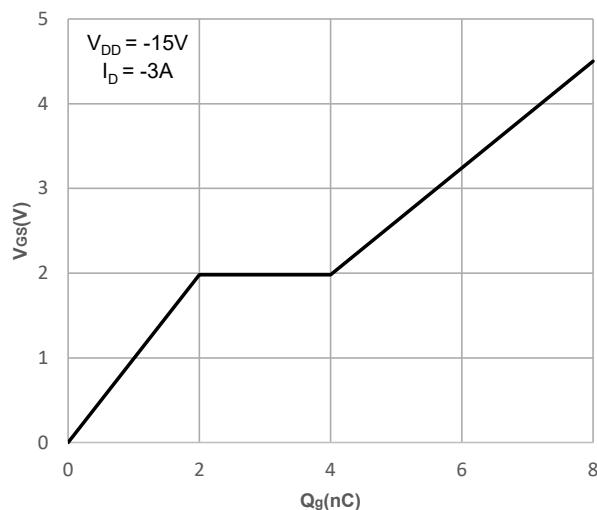
**Figure 3: On-resistance vs. Drain Current**



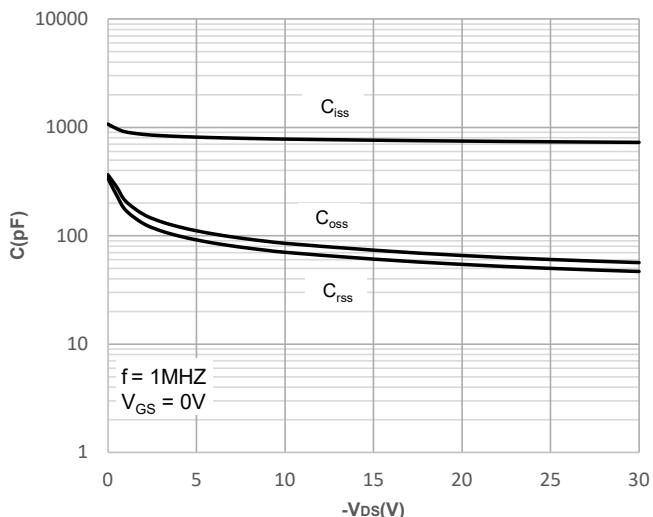
**Figure 4: Body Diode Characteristics**



**Figure 5: Gate Charge Characteristics**

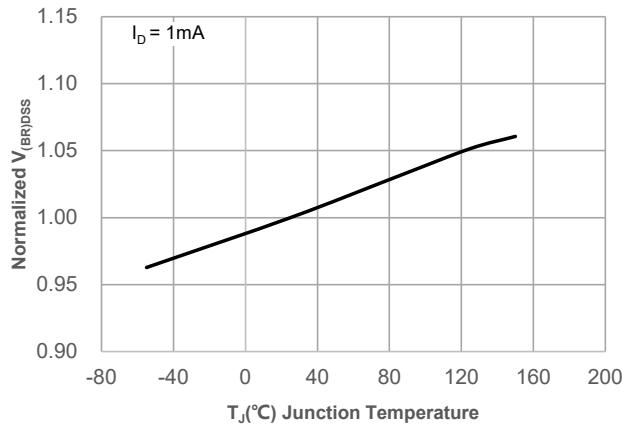


**Figure 6: Capacitance Characteristics**

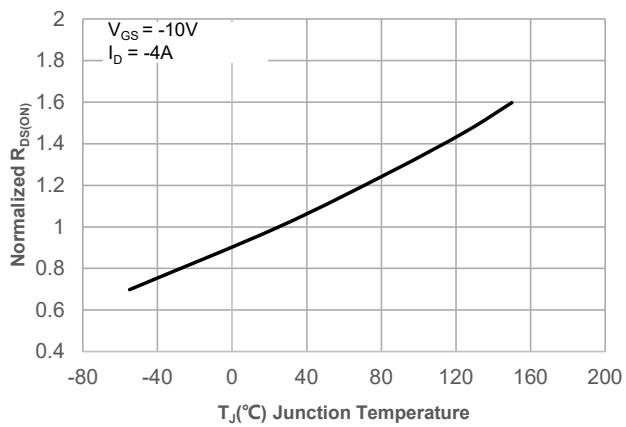


## Typical Performance Characteristics

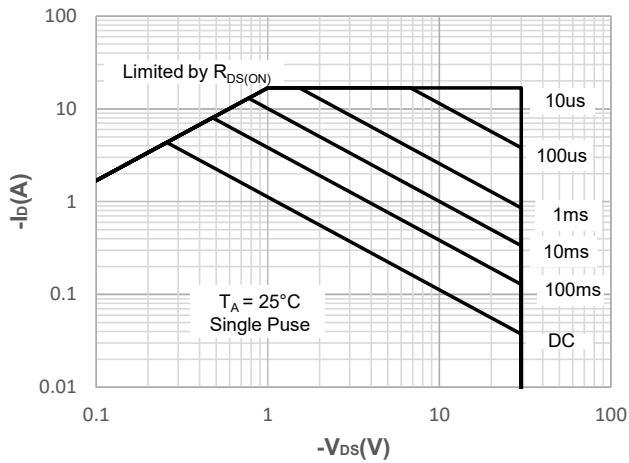
**Figure 7: Normalized Breakdown voltage vs. Junction Temperature**



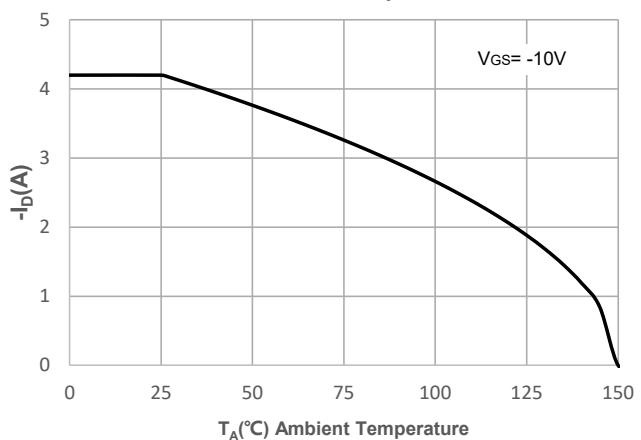
**Figure 8: Normalized on Resistance vs. Junction Temperature**



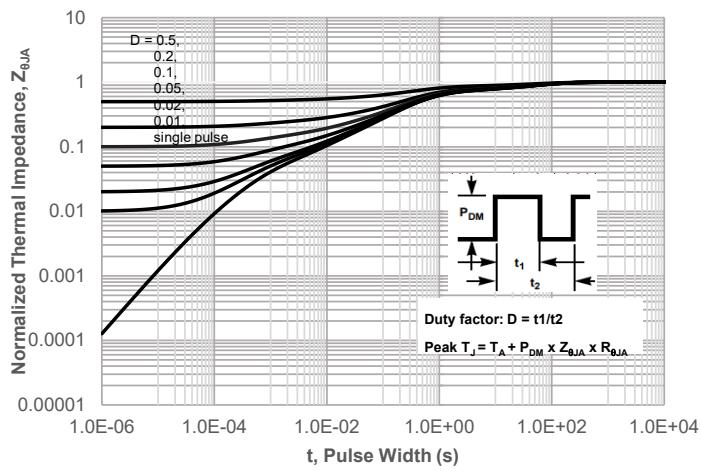
**Figure 9: Maximum Safe Operating Area**



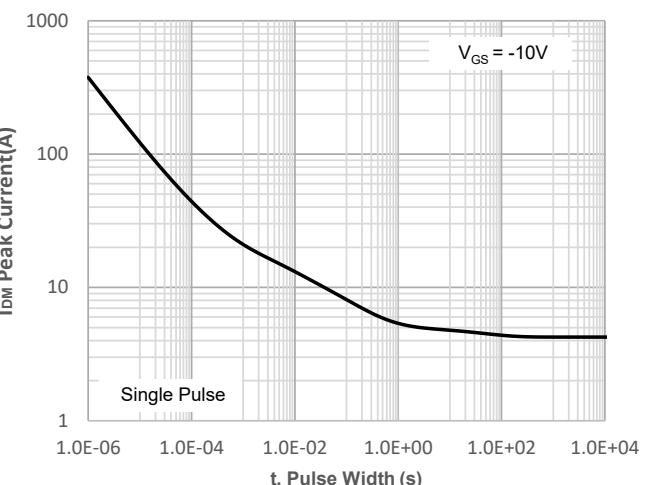
**Figure 10: Maximum Continuous Drian Current vs. Ambient Temperature**



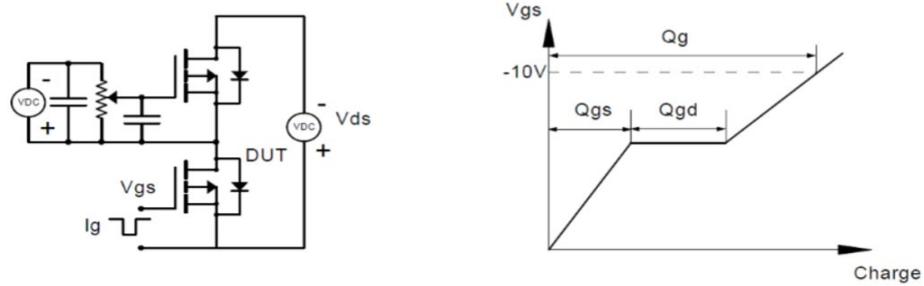
**Figure 11: Normalized Maximum Transient Thermal Impedance**



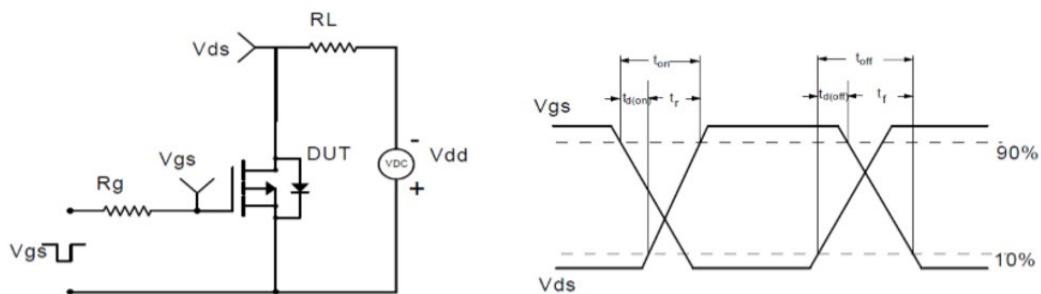
**Figure 12: Peak Current Capacity**



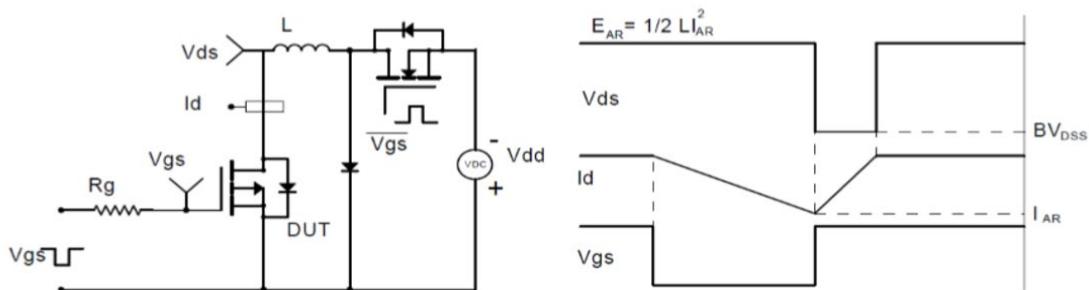
## Test Circuit



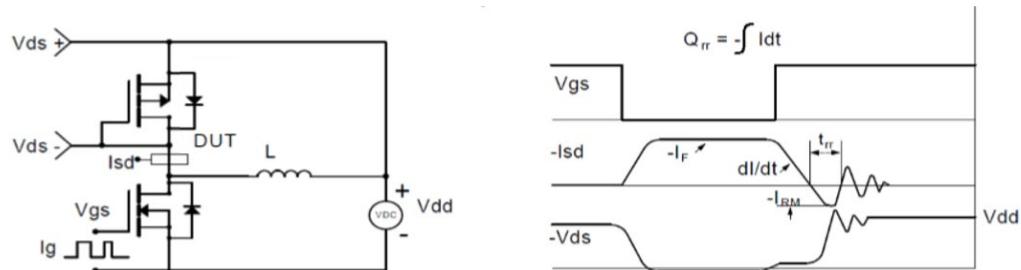
**Figure 1: Gate Charge Test Circuit & Waveform**



**Figure 2: Resistive Switching Test Circuit & Waveform**

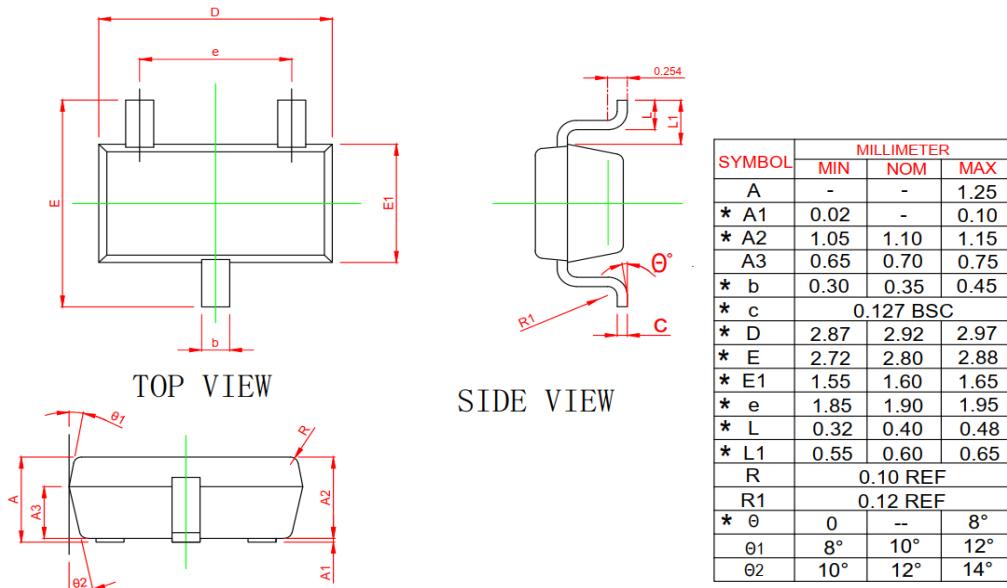


**Figure 3: Unclamped Inductive Switching Test Circuit& Waveform**



**Figure 4: Diode Recovery Test Circuit & Waveform**

## Package Mechanical Data(SOT-23-3L)



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